







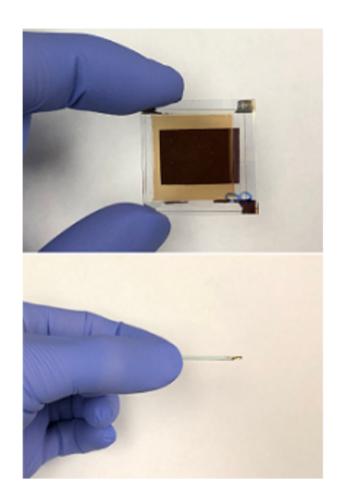
### Hyperfine Spectrometer

A sub-picometer resolution spectrometer in a compact package.

## .: Top Stories

#### Compact, Multifunctional Device Uses Infrared Light to **Deliver Images** Electrical engineers at the University of California, San Diego described

a thin, large-scale device that converts infrared light into images. The imager, among other applications, can be used to see through smog and smoke and to see through silicon wafers to inspect the quality and composition of electronic boards. Read Article

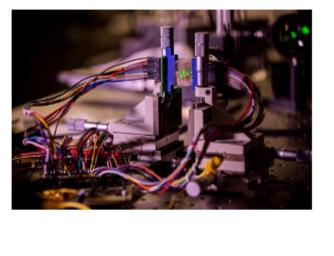


#### **Autonomous Vision** A real-time 3D tracking system developed at the University of Michigan may one day replace lidar and cameras in autonomous technologies.

Graphene-Based Tracking System May Streamline

The system combines transparent graphene-based light detectors and advanced neural networks to sense and image scenes in three dimensions. Read Article

Silicon Multiplexer to Advance THz-Based Communications

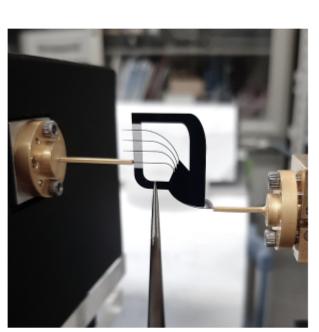


### data processing speeds and the next generation of communications —

An ultra-small silicon chip called a multiplexer is poised to increase

6G and beyond — as a result. The chip, developed by researchers from Osaka University and the University of Adelaide, is made from pure silicon and manages terahertz waves in the 300 GHz band.

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## Image Quality

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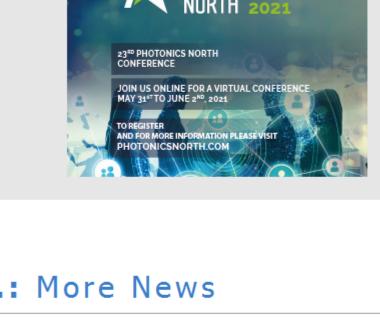
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# MKS Adds Optical Sensor Tech with Photon Control Acquisition Read Article

Nitride-Based MicroLED Emits Pure Red Light Read Article

EC Establishes Pan-Continental Laser Consortium Read Article

**Light Unites on IDL 2021** Read Article

Wed, May 26, 2021 1:00 PM - 2:00 PM EDT

Hybrid Microscopy Method Uses AI to Deliver Robust Images in Seconds Read Article

Freeform Optics for Imaging: Design Methods

.: Upcoming Webinars



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# industry will be discussed. Part 1 of the 2021 Freeform Optics Series.

Freeform Optics for Imaging: Manufacturing Methods Thu, May 27, 2021 1:00 PM - 2:00 PM EDT

In this talk Matt Davies, Ph.D., of UNC Charlotte, and John Lambropoulos, Ph.D., of the University of

The rise of freeform optics in imaging applications has led to optical systems with increased etendue,

more compact volumes, and superior performance. In this presentation, Jannick Rolland, Ph.D., and

Aaron Bauer, Ph.D., of the University of Rochester's Institute of Optics will provide an overview of the

Rochester, discuss the current methods employed for manufacturing freeform optics, as well as those methods' comparative strengths and the limitations. In particular, they examine the need for postprocessing (finishing) and its interactions with other manufacturing steps and methods. Part 2 of the

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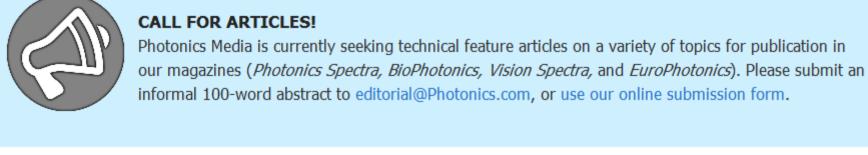


MID-SPATIAL

EREQUENCY ERRORS

Freeform Optics for Imaging: Mid-Spatial Frequency Errors

Wed, Jun 2, 2021 1:00 PM - 2:00 PM EDT Residual mid-spatial frequency (MSF) surface errors are common byproducts of the computercontrolled sub-aperture manufacturing techniques needed for fabrication of freeform optics. In this presentation, Thomas Suleski, Ph.D., provides an overview of MSF surface error signatures, specification methods, and performance impacts. Part 3 of the 2021 Freeform Optics Series.



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